


<b>Search Notes</b>  	<b>Application/Control No.</b>  10591707	<b>Applicant(s)/Patent Under Reexamination</b>  MIYOSHI, KENICHI
	<b>Examiner</b>  Nguyen, Hai V	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
455	11.1	02/17/2008	HN

SEARCH NOTES		
Search Notes	Date	Examiner
EAST search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) (see search history printout report)	02/17/2008	HN
Google search: OFDM TDD FDD relay mobile	01/17/2008	HN
EAST search updated	09/27/2008	HN
Interference search	09/27/2008	HN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
370	480	09/27/2008	HN

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